## Notice of References Cited Application/Control No. 09/998,713 Applicant(s)/Patent Under Reexamination YOON, HEUNG-SIK Examiner TUAN A PHAM Art Unit Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	4	US-6,535,748	03-2003	Vuorio et al.	455/552.1
	В	US-6,665,284	12-2003	Tran et al.	370/334
	С	US-2002/0123319	09-2002	Peterzell, Paul E.	455/296
	D	US-6,330,433	12-2001	Jager, Michael David .	455/277.2
	Ε	ÚS-6,191,724	02-2001	McEwan, Thomas E.	342/21
	F	US-6,697,605	02-2004	Atokawa et al.	455/82
	G	US-5,960,039	09-1999	Martin et al.	375/267
	Н	US-5,809,405	09-1998	Yamaura, Tomoya	455/101
	1	US-			
	j	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	Т			·		

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	·
	٧	
	W	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.